

Search Notes

Application/Control No.

10/776,672

Examiner

Binh X. Tran

Applicant(s)/Patent under
Reexamination

PAVEL ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated searched using USPAT, USPG-PUB, JPO, EPO, DERWENT database	3/2/2006	BT